

30V 1.5mohm N-channel SGT MOSFET

AKG3N015GL

Description:

This N channel SGT MOSFET has been designed to very low on-state resistance and maintain superior switching performance, especial for high efficiency power management applications.w

Features:

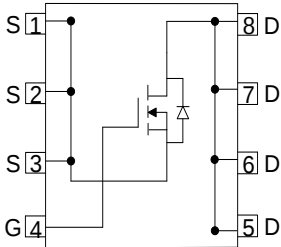
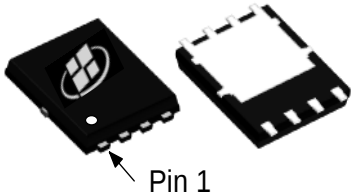
- Low FOM $R_{DS(ON)} \times Q_G$
- Ultra-low on-resistance
- RoHS compliant ^(Note 1)
- Halogen-free ^(Note 1)

Applications:

- Battery Management System
- Motor Drivers
- DC-DC Converter

Key Performance Parameters:

Parameter	Value	Unit
V_{DS}	30	V
$R_{DS(ON), max} @V_{GS} = 10V$	1.5	mΩ
I_D	165	A



Ordering Information:

Ordering Code	Package Type	Marking Code	Form	Packing
AKG3N015GL	PDFN5X6	AKG3N015GL	Tape Reel	See the detail package information

Notes:

1. Contact ALKAIDSEMI sales for detail information

Maximum Ratings ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Value	Units
V_{DS}	Drain-Source Voltage	30	V
I_D	Drain Current - Continuous ($T_C = 25^\circ\text{C}$) ^(Note 1)	165	A
	Drain Current - Continuous ($T_C = 100^\circ\text{C}$)	104	A
I_{DM}	Drain Current - Pulsed ^(Note 2)	530	A
V_{GS}	Gate-Source Voltage	± 20	V
E_{AS}	Single Pulsed Avalanche Energy ^(Note 3)	132	mJ
P_D	Power Dissipation ($T_C = 25^\circ\text{C}$)	69	W
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$

Thermal Characteristics

Symbol	Parameter	Value	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Steady-State	1.8	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Steady State ^(Note 4)	60	$^\circ\text{C/W}$

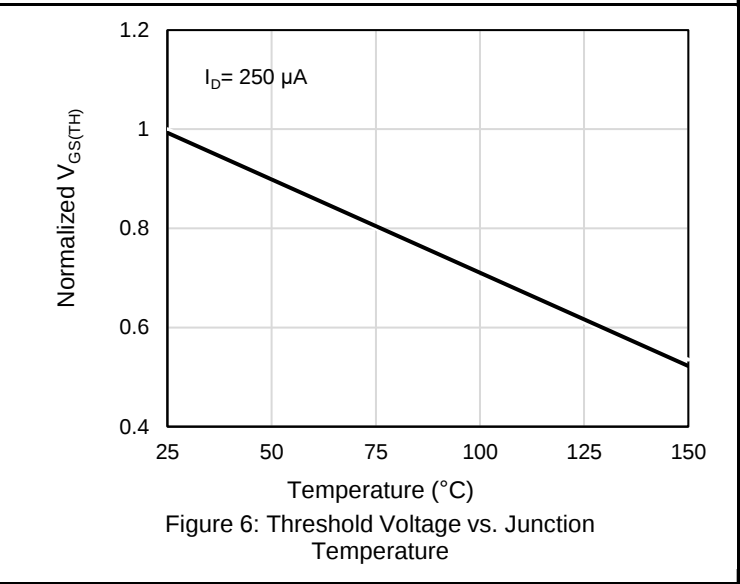
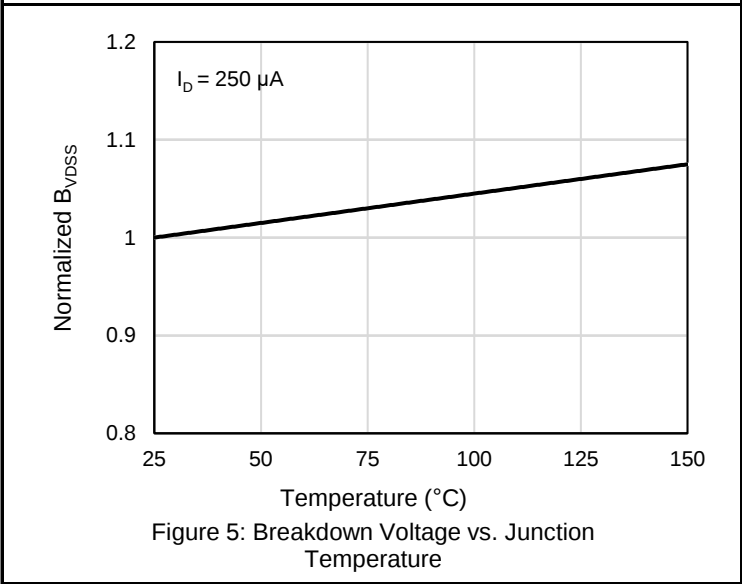
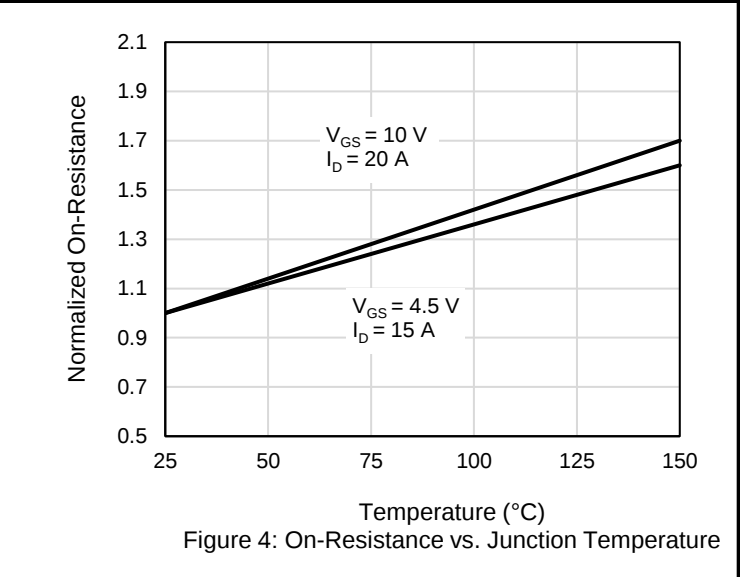
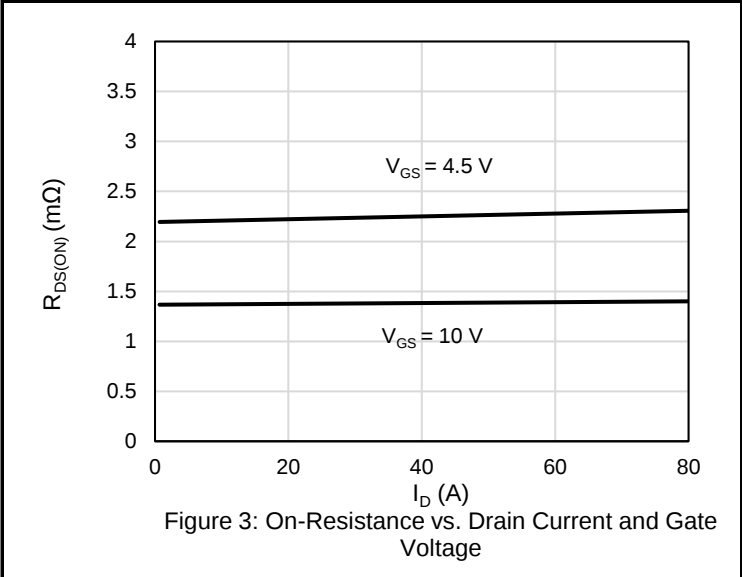
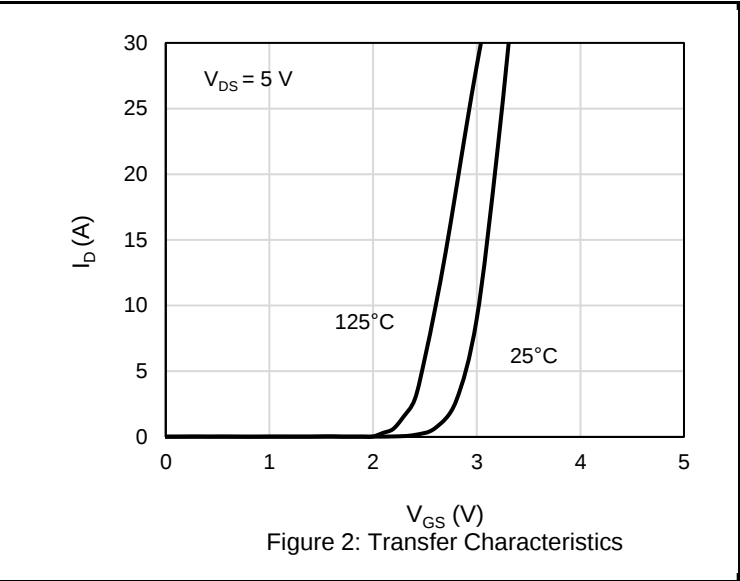
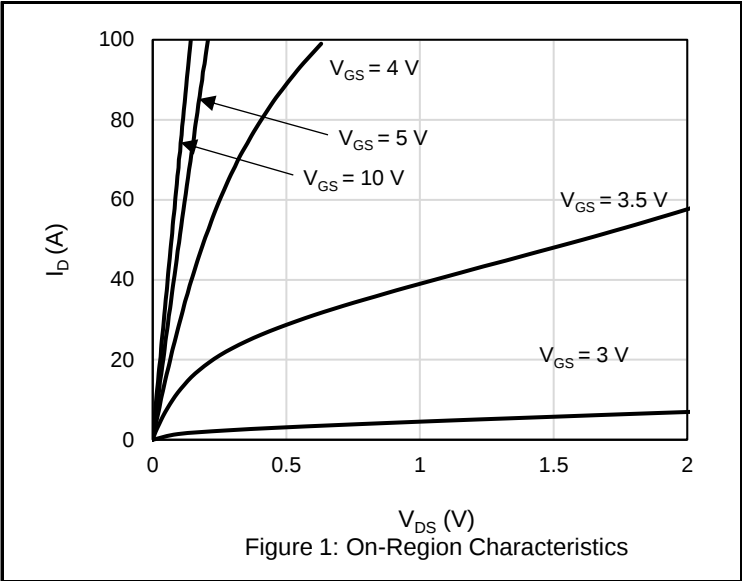
Notes:

1. The max drain current rating is package limited
2. Repetitive Rating: Pulse width limited by maximum junction temperature
3. $L = 0.5\text{ mH}$, $V_{DD} = 15\text{ V}$, $I_{AS} = 23\text{ A}$, $R_G = 25\ \Omega$, Starting $T_J = 25\ ^\circ\text{C}$
4. Mount on minimum PCB layout

Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Static Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA	30			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 30 V, V _{GS} = 0 V,			1	μA
I _{GSS}	Gate Leakage Current	V _{GS} = ± 20 V, V _{DS} = 0 V			±100	nA
V _{GS(TH)}	Gate Threshold voltage	V _{DS} = V _{GS} , I _D = 250 μA	1	1.7	2.5	V
R _{DS(ON)}	Drain-Source on-state resistance	V _{GS} = 10 V, I _D = 20 A		1.3	1.5	mΩ
		V _{GS} = 4.5 V, I _D = 15 A		2.2	2.8	mΩ
Dynamic Characteristics						
C _{ISS}	Input Capacitance	V _{DS} = 15 V, V _{GS} = 0 V, F = 1 MHz		2874		pF
C _{OSS}	Output Capacitance			1151		pF
C _{RSS}	Reverse Transfer Capacitance			76		pF
R _G	Gate Resistance	F = 1 MHz		1.6		Ω
Switching Characteristics						
T _{D(ON)}	Turn On Delay Time	V _{DD} = 15 V , R _L = 0.75 Ω, V _{GS} = 10 V, R _G =3 Ω		12		ns
T _R	Rise Time			48.5		ns
T _{D(OFF)}	Turn Off Delay Time			39.5		ns
T _F	Fall Time			14.5		ns
Q _G	Total Gate Charge	V _{DD} = 15 V , I _D = 20 A, V _{GS} = 10 V		46.5		nC
Q _{GS}	Gate-Source Charge			7.7		nC
Q _{GD}	Gate-Drain Charge			11		nC
Drain-Source Diode Characteristics and Maximum Ratings						
I _S	Maximum Continuous Body-Diode Forward Current				165	A
I _{SM}	Maximum Pulsed Body-Diode Forward Current				530	A
V _{SD}	Diode Forward Voltage	V _{GS} = 0 V, I _S = 1 A		0.65	1	V
T _{RR}	Reverse recovery time	V _{DD} = 20 V, I _D = 20 A, di/dt = 100 A/μs		46.1		ns
Q _{RR}	Reverse recovery charge			43.7		nC
I _{RRM}	Peak Reverse Recovery Current			1.6		A

Electrical Characteristics Diagrams



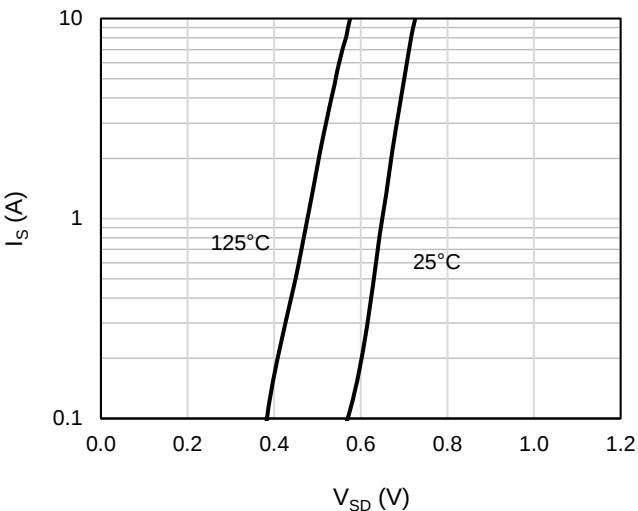


Figure 7: Body-Diode Characteristics

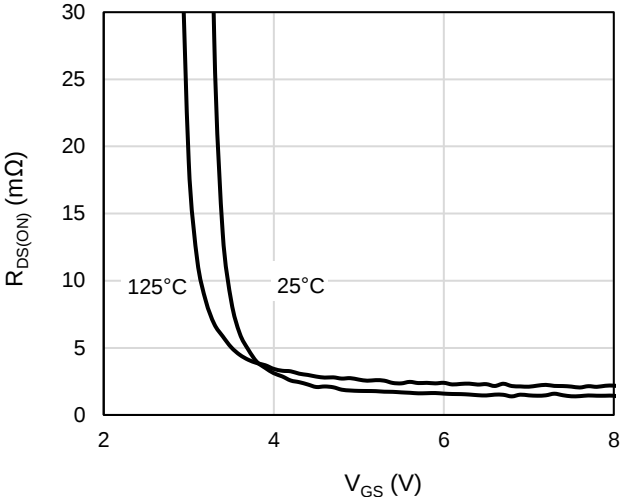


Figure 8: On-Resistance vs. Gate-Source Voltage

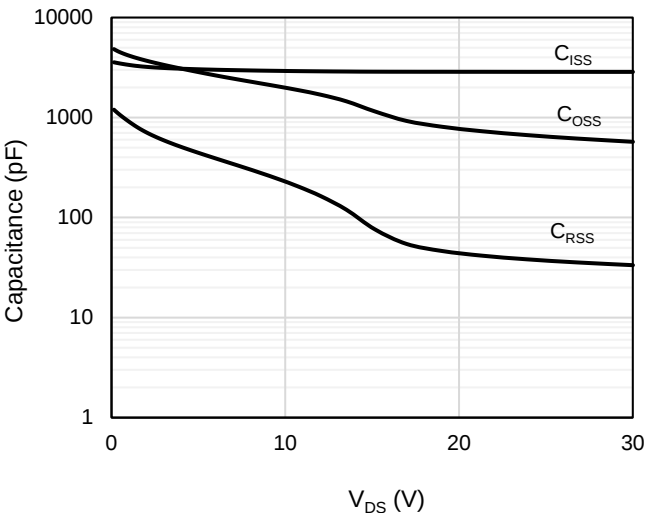


Figure 9: Capacitance Characteristics

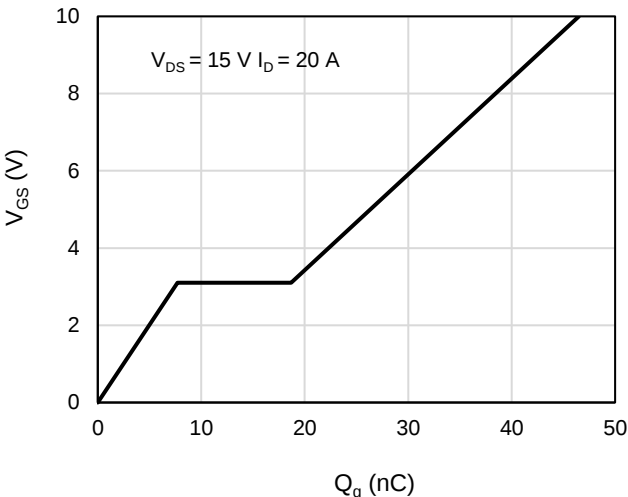


Figure 10: Gate-Charge Characteristics

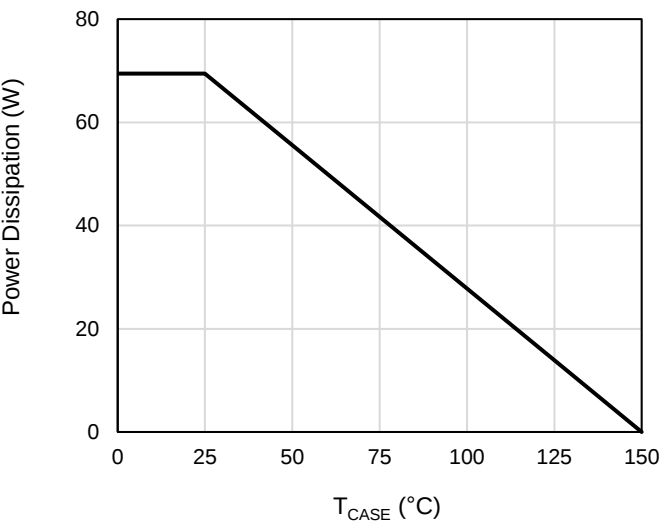


Figure 11: Power De-rating

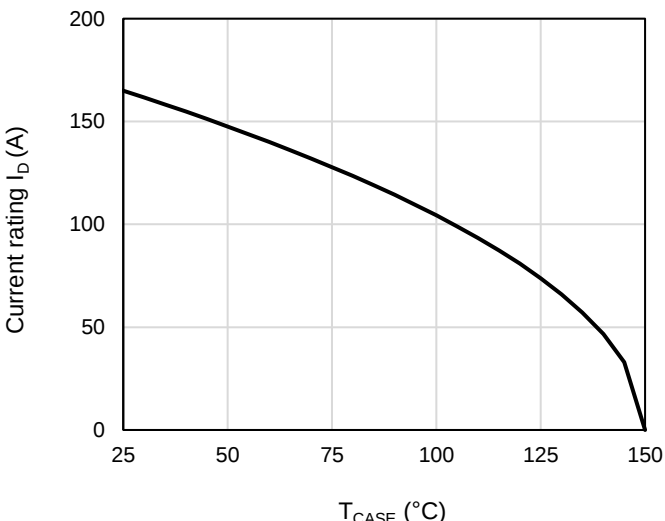
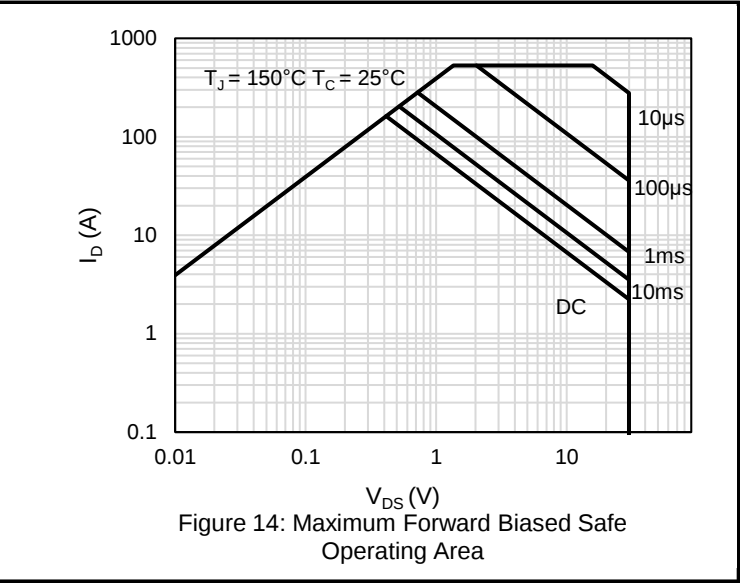
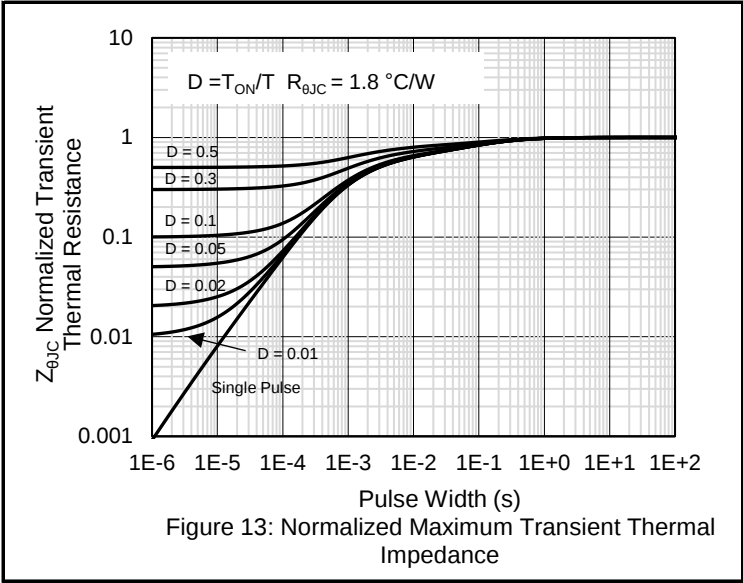
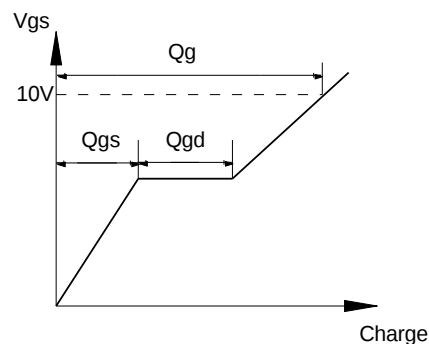
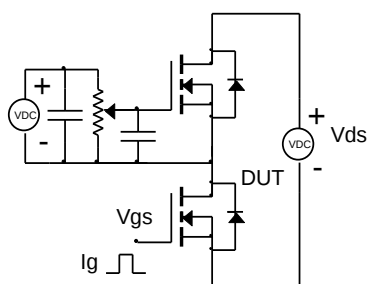


Figure 12: Current De-rating

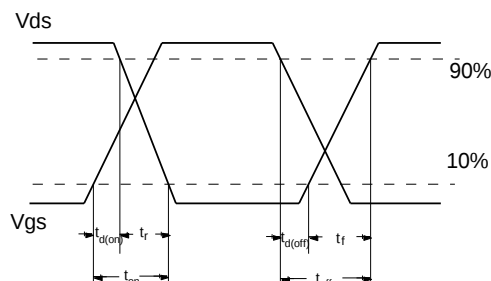
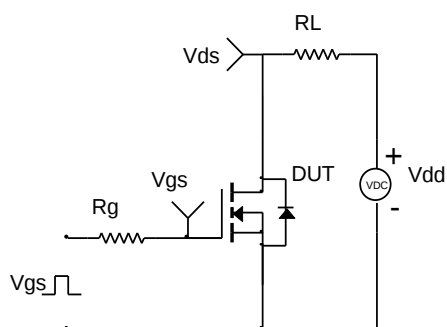


Test Circuit and Waveform

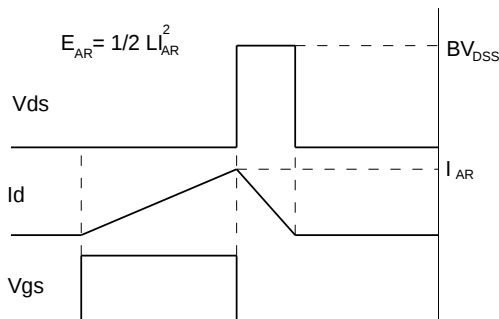
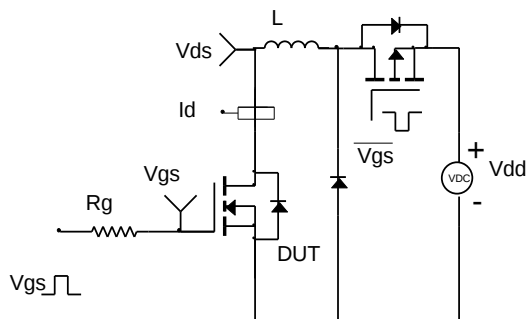
Gate Charge Test Circuit & Waveform



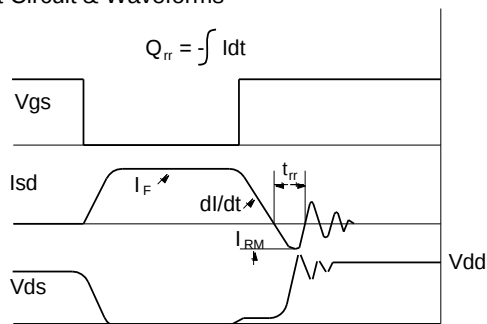
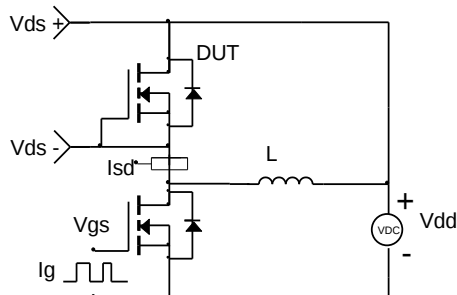
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Revision History

Revision	Release Date	Remark
Rev.1.1	2023/7/7	

Disclaimer

The information given in this document describes the independent performance of the product, but similar performance is not guaranteed under other working conditions, and cannot be guaranteed when installed with other products or equipment. To achieve the required performance of the product in actual scenarios, the customer should conduct a complete application test to assess the functionality of the product.

Alkaidsemi assumes no responsibility for equipment failures result from using products at values that exceed the ratings, operating conditions, or other parameters listed in the product specifications.

The product described in this specification is not applicable for aerospace or other applications which requires high reliability. Customers using or selling these products for use in medical, life-saving, or life-sustaining applications do so at their own risk and agree to fully indemnify.

Due to product or technical improvements, the information described or contained herein may be changed without prior notice.